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| Substitute for form 1449A/PTO<br><b>INFORMATION DISCLOSURE<br/>STATEMENT BY APPLICANT</b><br>(as many sheets as necessary) | Complete if Known                |                   |
|  | Application Number               | 10/081439         |
|  | Filing Date                      | February 20, 2002 |
|  | First Named Inventor             | Ahn, Kie          |
|  | Group Art Unit                   | 2818              |
|  | Examiner Name                    | Unknown           |
| Sheet 1 of 1   | Attorney Docket No: 01303.046US1 |                   |

| US PATENT DOCUMENTS |                     |                  |   |       |          |                            |
|---------------------|---------------------|------------------|---|-------|----------|----------------------------|
| Examiner Initial *  | USP Document Number | Publication Date | Name of Patentee or Applicant of cited Document | Class | Subclass | Filing Date If Appropriate |

| FOREIGN PATENT DOCUMENTS |                     |                  |   |       |          |    |
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| Examiner Initials *      | Foreign Document No | Publication Date | Name of Patentee or Applicant of cited Document | Class | Subclass | T* |

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| Examiner Initials *                                | Cite No | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.      | T* |
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not provided

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| EXAMINER | <i>Douglas With</i> | DATE CONSIDERED | <i>9 Mar 04</i> |
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